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Understanding Embedded - Microprocessors

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	MPC8xx
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	80MHz
Co-Processors/DSP	Communications; CPM
RAM Controllers	DRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10Mbps (2), 10/100Mbps (1)
SATA	-
USB	-
Voltage - I/O	3.3V
Operating Temperature	0°C ~ 95°C (TA)
Security Features	-
Package / Case	357-BBGA
Supplier Device Package	357-PBGA (25x25)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/kmpc860dpzq80d4

Table 6. DC Electrical Specifications (continued)

Characteristic	Symbol	Min	Max	Unit
Input leakage current, V_{in} = 3.6 V (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input leakage current, V_{in} = 0 V (except TMS, $\overline{\text{TRST}}$, DSCK, and DSDI pins)	I_{In}	—	10	µA
Input capacitance[2]	C_{in}	—	20	pF
Output high voltage, I_{OH} = –2.0 mA, V_{DDH} = 3.0 V (except XTAL, XFC, and open-drain pins)	V_{OH}	2.4	—	V
Output low voltage I_{OL} = 2.0 mA, CLKOUT I_{OL} = 3.2 mA [3] I_{OL} = 5.3 mA [4] I_{OL} = 7.0 mA, TXD1/PA14, TXD2/PA12 I_{OL} = 8.9 mA, $\overline{\text{TS}}$, $\overline{\text{TA}}$, $\overline{\text{TEA}}$, $\overline{\text{BI}}$, $\overline{\text{BB}}$, $\overline{\text{HRESET}}$, $\overline{\text{SRESET}}$	V_{OL}	—	0.5	V

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[1] V_{IL}(max) for the I^2C interface is 0.8 V rather than the 1.5 V as specified in the I^2C standard.

[2] Input capacitance is periodically sampled.

[3] A(0:31), TSIZ0/$\overline{\text{REG}}$, TSIZ1, D(0:31), DP(0:3)/$\overline{\text{IRQ}}$(3:6), RD/$\overline{\text{WR}}$, $\overline{\text{BURST}}$, $\overline{\text{RSV}}$/$\overline{\text{IRQ2}}$, IP_B(0:1)/IWP(0:1)/VFLS(0:1), IP_B2/IOIS16_B/AT2, IP_B3/IWP2/VF2, IP_B4/LWP0/VF0, IP_B5/LWP1/VF1, IP_B6/DSDI/AT0, IP_B7/PTR/AT3, RXD1/PA15, RXD2/PA13, L1TXDB/PA11, L1RXDB/PA10, L1TXDA/PA9, L1RXDA/PA8, TIN1/L1RCLKA/BRGO1/CLK1/PA7, BRGCLK1/$\overline{\text{TOUT1}}$/CLK2/PA6, TIN2/L1TCLKA/BRGO2/CLK3/PA5, $\overline{\text{TOUT2}}$/CLK4/PA4, TIN3/BRGO3/CLK5/PA3, BRGCLK2/L1RCLKB/$\overline{\text{TOUT3}}$/CLK6/PA2, TIN4/BRGO4/CLK7/PA1, L1TCLKB/$\overline{\text{TOUT4}}$/CLK8/PA0, $\overline{\text{REJCT1}}$/$\overline{\text{SPISEL}}$/PB31, SPICLK/PB30,SPIMOSI/PB29, BRGO4/SPIMISO/PB28, BRGO1/I2CSDA/PB27, BRGO2/I2CSCL/PB26, SMTXD1/PB25, SMRXD1/PB24, $\overline{\text{SMSYN1}}$/$\overline{\text{SDACK1}}$/PB23, $\overline{\text{SMSYN2}}$/$\overline{\text{SDACK2}}$/PB22, SMTXD2/L1CLKOB/PB21, SMRXD2/L1CLKOA/PB20, L1ST1/$\overline{\text{RTS1}}$/PB19, L1ST2/$\overline{\text{RTS2}}$/PB18, L1ST3/$\overline{\text{L1RQB}}$/PB17, L1ST4/$\overline{\text{L1RQA}}$/PB16, BRGO3/PB15, $\overline{\text{RSTRT1}}$/PB14, L1ST1/$\overline{\text{RTS1}}$/$\overline{\text{DREQ0}}$/PC15, L1ST2/$\overline{\text{RTS2}}$/$\overline{\text{DREQ1}}$/PC14, L1ST3/$\overline{\text{L1RQB}}$/PC13, L1ST4/$\overline{\text{L1RQA}}$/PC12, $\overline{\text{CTS1}}$/PC11, $\overline{\text{TGATE1}}$/$\overline{\text{CD1}}$/PC10, $\overline{\text{CTS2}}$/PC9, $\overline{\text{TGATE2}}$/$\overline{\text{CD2}}$/PC8, $\overline{\text{SDACK2}}$/L1TSYNCB/PC7, L1RSYNCB/PC6, $\overline{\text{SDACK1}}$/L1TSYNCA/PC5, L1RSYNCA/PC4, PD15, PD14, PD13, PD12, PD11, PD10, PD9, PD8, PD5, PD6, PD7, PD4, PD3, MII_MDC, MII_TX_ER, MII_EN, MII_MDIO, and MII_TXD[0:3]

[4] $\overline{\text{BDIP}}$/$\overline{\text{GPL\_B}}$(5), $\overline{\text{BR}}$, $\overline{\text{BG}}$, FRZ/$\overline{\text{IRQ6}}$, $\overline{\text{CS}}$(0:5), $\overline{\text{CS}}$(6)/$\overline{\text{CE}}$(1)_B, $\overline{\text{CS}}$(7)/$\overline{\text{CE}}$(2)_B, $\overline{\text{WE0}}$/$\overline{\text{BS\_B0}}$/$\overline{\text{IORD}}$, $\overline{\text{WE1}}$/$\overline{\text{BS\_B1}}$/$\overline{\text{IOWR}}$, $\overline{\text{WE2}}$/$\overline{\text{BS\_B2}}$/$\overline{\text{PCOE}}$, $\overline{\text{WE3}}$/$\overline{\text{BS\_B3}}$/$\overline{\text{PCWE}}$, $\overline{\text{BS\_A}}$(0:3), $\overline{\text{GPL\_A0}}$/$\overline{\text{GPL\_B0}}$, $\overline{\text{OE}}$/$\overline{\text{GPL\_A1}}$/$\overline{\text{GPL\_B1}}$, $\overline{\text{GPL\_A}}$(2:3)/$\overline{\text{GPL\_B}}$(2:3)/$\overline{\text{CS}}$(2:3), UPWAITA/$\overline{\text{GPL\_A4}}$, UPWAITB/$\overline{\text{GPL\_B4}}$, $\overline{\text{GPL\_A5}}$, ALE_A, $\overline{\text{CE}}$1_A, $\overline{\text{CE}}$2_A, ALE_B/DSCK/AT1, OP(0:1), OP2/MODCK1/$\overline{\text{STS}}$, OP3/MODCK2/DSDO, and BADDR(28:30)

7 Thermal Calculation and Measurement

For the following discussions, $P_D = (V_{DD} \times I_{DD}) + PI/O$, where PI/O is the power dissipation of the I/O drivers.

7.1 Estimation with Junction-to-Ambient Thermal Resistance

An estimation of the chip junction temperature, T_J, in ºC can be obtained from the equation:

$$T_J = T_A + (R_{\theta JA} \times P_D)$$

where:

T_A = ambient temperature (ºC)
$R_{\theta JA}$ = package junction-to-ambient thermal resistance (ºC/W)
P_D = power dissipation in package

The junction-to-ambient thermal resistance is an industry standard value which provides a quick and easy estimation of thermal performance. However, the answer is only an estimate; test cases have demonstrated that errors of a factor of two (in the quantity $T_J - T_A$) are possible.

7.2 Estimation with Junction-to-Case Thermal Resistance

Historically, the thermal resistance has frequently been expressed as the sum of a junction-to-case thermal resistance and a case-to-ambient thermal resistance:

$$R_{\theta JA} = R_{\theta JC} + R_{\theta CA}$$

where:

$R_{\theta JA}$ = junction-to-ambient thermal resistance (ºC/W)
$R_{\theta JC}$ = junction-to-case thermal resistance (ºC/W)
$R_{\theta CA}$ = case-to-ambient thermal resistance (ºC/W)

$R_{\theta JC}$ is device related and cannot be influenced by the user. The user adjusts the thermal environment to affect the case-to-ambient thermal resistance, $R_{\theta CA}$. For instance, the user can change the airflow around the device, add a heat sink, change the mounting arrangement on the printed-circuit board, or change the thermal dissipation on the printed-circuit board surrounding the device. This thermal model is most useful for ceramic packages with heat sinks where some 90% of the heat flows through the case and the heat sink to the ambient environment. For most packages, a better model is required.

7.3 Estimation with Junction-to-Board Thermal Resistance

A simple package thermal model which has demonstrated reasonable accuracy (about 20%) is a two-resistor model consisting of a junction-to-board and a junction-to-case thermal resistance. The junction-to-case thermal resistance covers the situation where a heat sink is used or where a substantial amount of heat is dissipated from the top of the package. The junction-to-board thermal resistance describes the thermal performance when most of the heat is conducted to the printed-circuit board. It has been observed that the thermal performance of most plastic packages, especially PBGA packages, is strongly dependent on the board temperature; see Figure 2.

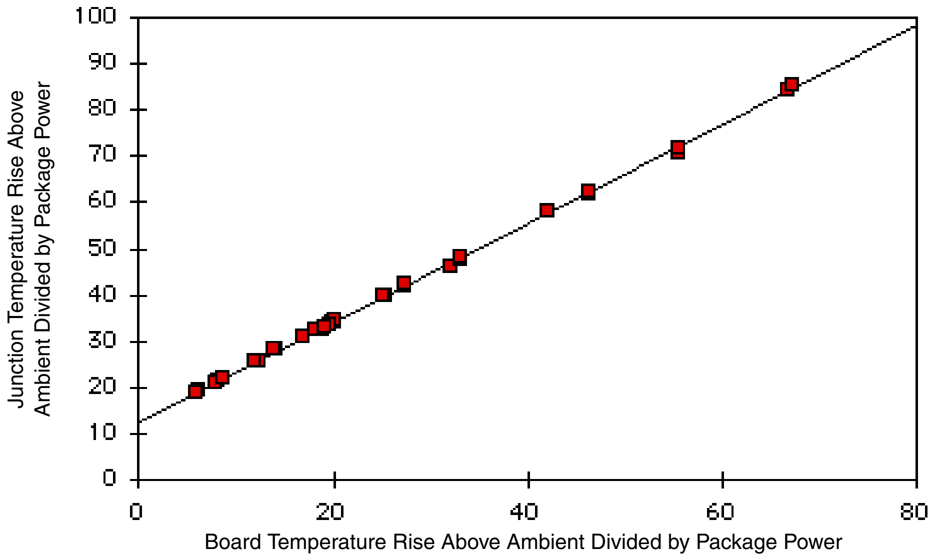

Figure 2. Effect of Board Temperature Rise on Thermal Behavior

If the board temperature is known, an estimate of the junction temperature in the environment can be made using the following equation:

$$T_J = T_B + (R_{\theta JB} \times P_D)$$

where:

$R_{\theta JB}$ = junction-to-board thermal resistance (°C/W)
T_B = board temperature (°C)
P_D = power dissipation in package

If the board temperature is known and the heat loss from the package case to the air can be ignored, acceptable predictions of junction temperature can be made. For this method to work, the board and board mounting must be similar to the test board used to determine the junction-to-board thermal resistance, namely a 2s2p (board with a power and a ground plane) and by attaching the thermal balls to the ground plane.

7.4 Estimation Using Simulation

When the board temperature is not known, a thermal simulation of the application is needed. The simple two-resistor model can be used with the thermal simulation of the application [2], or a more accurate and complex model of the package can be used in the thermal simulation.

7.5 Experimental Determination

To determine the junction temperature of the device in the application after prototypes are available, the thermal characterization parameter (Ψ_{JT}) can be used to determine the junction temperature with a measurement of the temperature at the top center of the package case using the following equation:

$$T_J = T_T + (\Psi_{JT} \times P_D)$$

where:

Ψ_{JT} = thermal characterization parameter
T_T = thermocouple temperature on top of package
P_D = power dissipation in package

The thermal characterization parameter is measured per JEDEC JESD51-2 specification using a 40 gauge type T thermocouple epoxied to the top center of the package case. The thermocouple should be positioned so that the thermocouple junction rests on the package. A small amount of epoxy is placed over the thermocouple junction and over 1 mm of wire extending from the junction. The thermocouple wire is placed flat against the package case to avoid measurement errors caused by cooling effects of the thermocouple wire.

7.6 References

Semiconductor Equipment and Materials International 805 East Middlefield Rd. Mountain View, CA 94043	(415) 964-5111
MIL-SPEC and EIA/JESD (JEDEC) Specifications (Available from Global Engineering Documents)	800-854-7179 or 303-397-7956
JEDEC Specifications	http://www.jedec.org

1. C.E. Triplett and B. Joiner, “An Experimental Characterization of a 272 PBGA Within an Automotive Engine Controller Module,” Proceedings of SemiTherm, San Diego, 1998, pp. 47–54.
2. B. Joiner and V. Adams, “Measurement and Simulation of Junction to Board Thermal Resistance and Its Application in Thermal Modeling,” Proceedings of SemiTherm, San Diego, 1999, pp. 212–220.

8 Layout Practices

Each V_{DD} pin on the MPC860 should be provided with a low-impedance path to the board’s supply. Each GND pin should likewise be provided with a low-impedance path to ground. The power supply pins drive distinct groups of logic on the chip. The V_{DD} power supply should be bypassed to ground using at least four 0.1 µF-bypass capacitors located as close as possible to the four sides of the package. The capacitor leads and associated printed circuit traces connecting to chip V_{DD} and GND should be kept to less than half an inch per capacitor lead. A four-layer board employing two inner layers as V_{CC} and GND planes is recommended.

All output pins on the MPC860 have fast rise and fall times. Printed circuit (PC) trace interconnection length should be minimized in order to minimize undershoot and reflections caused by these fast output switching times. This recommendation particularly applies to the address and data buses. Maximum PC trace lengths of 6 inches are recommended. Capacitance calculations should consider all device loads as well as parasitic capacitances due to the PC traces. Attention to proper PCB layout and bypassing becomes especially critical in systems with higher capacitive loads because these loads create higher transient currents in the V_{CC} and GND circuits. Pull up all unused inputs or signals that will be inputs during reset. Special care should be taken to minimize the noise levels on the PLL supply pins.

Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B9	CLKOUT to A(0:31), BADDR(28:30), RD/$\overline{\mathrm{WR}}$, $\overline{\mathrm{BURST}}$, D(0:31), DP(0:3), TSIZ(0:1), $\overline{\mathrm{REG}}$, $\overline{\mathrm{RSV}}$, AT(0:3), PTR High-Z	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B11	CLKOUT to $\overline{\mathrm{TS}}$, $\overline{\mathrm{BB}}$ assertion	7.58	13.58	6.25	12.25	5.00	11.00	3.80	11.29	ns
B11a	CLKOUT to $\overline{\mathrm{TA}}$, $\overline{\mathrm{BI}}$ assertion (when driven by the memory controller or PCMCIA interface)	2.50	9.25	2.50	9.25	2.50	9.25	2.50	9.75	ns
B12	CLKOUT to $\overline{\mathrm{TS}}$, $\overline{\mathrm{BB}}$ negation	7.58	14.33	6.25	13.00	5.00	11.75	3.80	8.54	ns
B12a	CLKOUT to $\overline{\mathrm{TA}}$, $\overline{\mathrm{BI}}$ negation (when driven by the memory controller or PCMCIA interface)	2.50	11.00	2.50	11.00	2.50	11.00	2.50	9.00	ns
B13	CLKOUT to $\overline{\mathrm{TS}}$, $\overline{\mathrm{BB}}$ High-Z	7.58	21.58	6.25	20.25	5.00	19.00	3.80	14.04	ns
B13a	CLKOUT to $\overline{\mathrm{TA}}$, $\overline{\mathrm{BI}}$ High-Z (when driven by the memory controller or PCMCIA interface)	2.50	15.00	2.50	15.00	2.50	15.00	2.50	15.00	ns
B14	CLKOUT to $\overline{\mathrm{TEA}}$ assertion	2.50	10.00	2.50	10.00	2.50	10.00	2.50	9.00	ns
B15	CLKOUT to $\overline{\mathrm{TEA}}$ High-Z	2.50	15.00	2.50	15.00	2.50	15.00	2.50	15.00	ns
B16	$\overline{\mathrm{TA}}$, $\overline{\mathrm{BI}}$ valid to CLKOUT (setup time)	9.75	—	9.75	—	9.75	—	6.00	—	ns
B16a	$\overline{\mathrm{TEA}}$, $\overline{\mathrm{KR}}$, $\overline{\mathrm{RETRY}}$, $\overline{\mathrm{CR}}$ valid to CLKOUT (setup time)	10.00	—	10.00	—	10.00	—	4.50	—	ns
B16b	$\overline{\mathrm{BB}}$, $\overline{\mathrm{BG}}$, $\overline{\mathrm{BR}}$, valid to CLKOUT (setup time)[5]	8.50	—	8.50	—	8.50	—	4.00	—	ns
B17	CLKOUT to $\overline{\mathrm{TA}}$, $\overline{\mathrm{TEA}}$, $\overline{\mathrm{BI}}$, $\overline{\mathrm{BB}}$, $\overline{\mathrm{BG}}$, $\overline{\mathrm{BR}}$ valid (hold time)	1.00	—	1.00	—	1.00	—	2.00	—	ns
B17a	CLKOUT to $\overline{\mathrm{KR}}$, $\overline{\mathrm{RETRY}}$, $\overline{\mathrm{CR}}$ valid (hold time)	2.00	—	2.00	—	2.00	—	2.00	—	ns
B18	D(0:31), DP(0:3) valid to CLKOUT rising edge (setup time)[6]	6.00	—	6.00	—	6.00	—	6.00	—	ns
B19	CLKOUT rising edge to D(0:31), DP(0:3) valid (hold time)[6]	1.00	—	1.00	—	1.00	—	2.00	—	ns
B20	D(0:31), DP(0:3) valid to CLKOUT falling edge (setup time)[7]	4.00	—	4.00	—	4.00	—	4.00	—	ns
B21	CLKOUT falling edge to D(0:31), DP(0:3) valid (hold time)[7]	2.00	—	2.00	—	2.00	—	2.00	—	ns
B22	CLKOUT rising edge to $\overline{\mathrm{CS}}$ asserted GPCM ACS = 00	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.04	ns
B22a	CLKOUT falling edge to $\overline{\mathrm{CS}}$ asserted GPCM ACS = 10, TRLX = 0	—	8.00	—	8.00	—	8.00	—	8.00	ns
B22b	CLKOUT falling edge to $\overline{\mathrm{CS}}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 0	7.58	14.33	6.25	13.00	5.00	11.75	3.80	10.54	ns
B22c	CLKOUT falling edge to $\overline{\mathrm{CS}}$ asserted GPCM ACS = 11, TRLX = 0, EBDF = 1	10.86	17.99	8.88	16.00	7.00	14.13	5.18	12.31	ns

Table 7. Bus Operation Timings (continued)

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
B29d	$\overline{\text{WE}}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 0	43.45	—	35.5	—	28.00	—	20.73	—	ns
B29e	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	—	35.5	—	28.00	—	29.73	—	ns
B29f	$\overline{\text{WE}}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, EBDF = 1	8.86	—	6.88	—	5.00	—	3.18	—	ns
B29g	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	8.86	—	6.88	—	5.00	—	3.18	—	ns
B29h	$\overline{\text{WE}}$(0:3) negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B29i	$\overline{\text{CS}}$ negated to D(0:31), DP(0:3) High-Z GPCM write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B30	$\overline{\text{CS}}$, $\overline{\text{WE}}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access[8]	5.58	—	4.25	—	3.00	—	1.79	—	ns
B30a	$\overline{\text{WE}}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM, write access, TRLX = 0, CSNT = 1, $\overline{\text{CS}}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1 ACS = 10, or ACS = 11, EBDF = 0	13.15	—	10.50	—	8.00	—	5.58	—	ns
B30b	$\overline{\text{WE}}$(0:3) negated to A(0:31), invalid GPCM BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT = 1. $\overline{\text{CS}}$ negated to A(0:31), Invalid GPCM, write access, TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 0	43.45	—	35.50	—	28.00	—	20.73	—	ns
B30c	$\overline{\text{WE}}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 0, CSNT = 1. $\overline{\text{CS}}$ negated to A(0:31) invalid GPCM write access, TRLX = 0, CSNT = 1, ACS = 10, ACS = 11, EBDF = 1	8.36	—	6.38	—	4.50	—	2.68	—	ns
B30d	$\overline{\text{WE}}$(0:3) negated to A(0:31), BADDR(28:30) invalid GPCM write access, TRLX = 1, CSNT =1. $\overline{\text{CS}}$ negated to A(0:31) invalid GPCM write access TRLX = 1, CSNT = 1, ACS = 10, or ACS = 11, EBDF = 1	38.67	—	31.38	—	24.50	—	17.83	—	ns
B31	CLKOUT falling edge to $\overline{\text{CS}}$ valid—as requested by control bit CST4 in the corresponding word in UPM	1.50	6.00	1.50	6.00	1.50	6.00	1.50	6.00	ns

Table 10 shows the PCMCIA port timing for the MPC860.

Table 10. PCMCIA Port Timing

Num	Characteristic	33 MHz		40 MHz		50 MHz		66 MHz		Unit
		Min	Max	Min	Max	Min	Max	Min	Max	
P57	CLKOUT to OPx valid	—	19.00	—	19.00	—	19.00	—	19.00	ns
P58	$\overline{\text{HRESET}}$ negated to OPx drive[1]	25.73	—	21.75	—	18.00	—	14.36	—	ns
P59	IP_Xx valid to CLKOUT rising edge	5.00	—	5.00	—	5.00	—	5.00	—	ns
P60	CLKOUT rising edge to IP_Xx invalid	1.00	—	1.00	—	1.00	—	1.00	—	ns

[1] OP2 and OP3 only.

Figure 28 provides the PCMCIA output port timing for the MPC860.

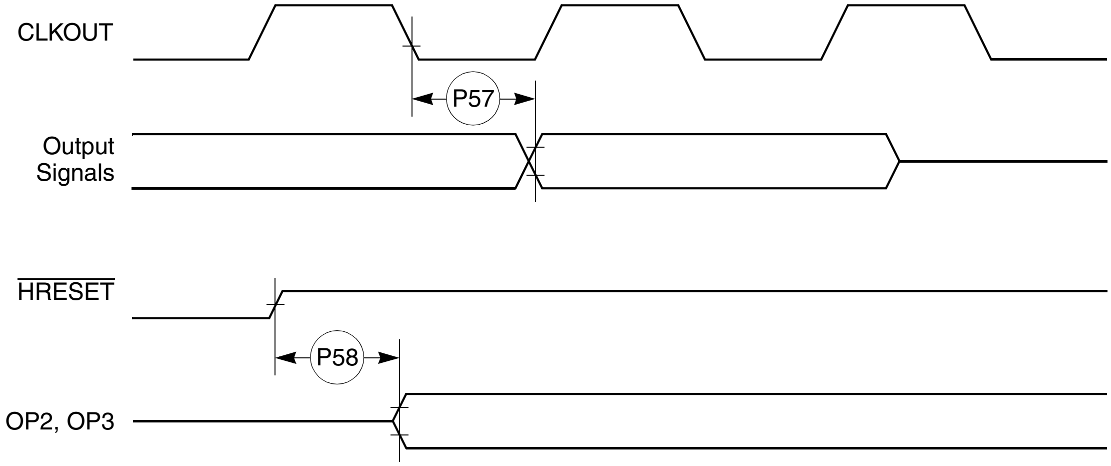

Figure 28. PCMCIA Output Port Timing

Figure 29 provides the PCMCIA output port timing for the MPC860.

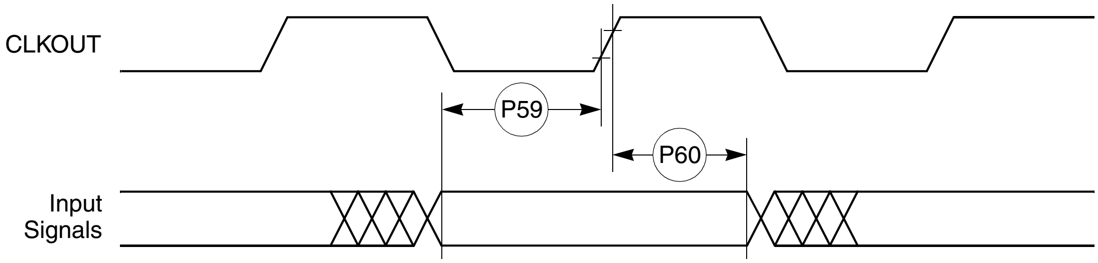

Figure 29. PCMCIA Input Port Timing

Table 11 shows the debug port timing for the MPC860.

Table 11. Debug Port Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
P61	DSCK cycle time	3 × $T_{CLOCKOUT}$	—	—
P62	DSCK clock pulse width	1.25 × $T_{CLOCKOUT}$	—	—
P63	DSCK rise and fall times	0.00	3.00	ns
P64	DSDI input data setup time	8.00	—	ns
P65	DSDI data hold time	5.00	—	ns
P66	DSCK low to DSDO data valid	0.00	15.00	ns
P67	DSCK low to DSDO invalid	0.00	2.00	ns

Figure 30 provides the input timing for the debug port clock.

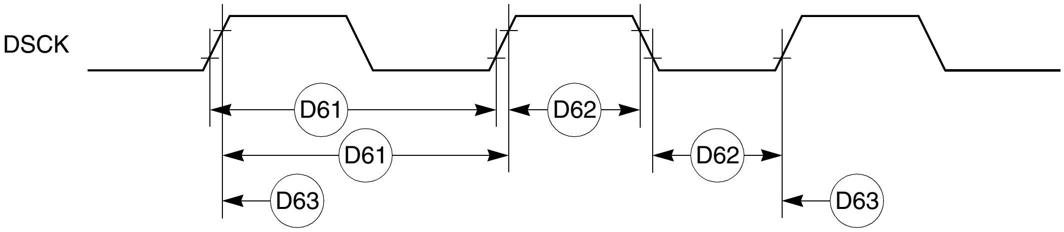

Figure 30. Debug Port Clock Input Timing

Figure 31 provides the timing for the debug port.

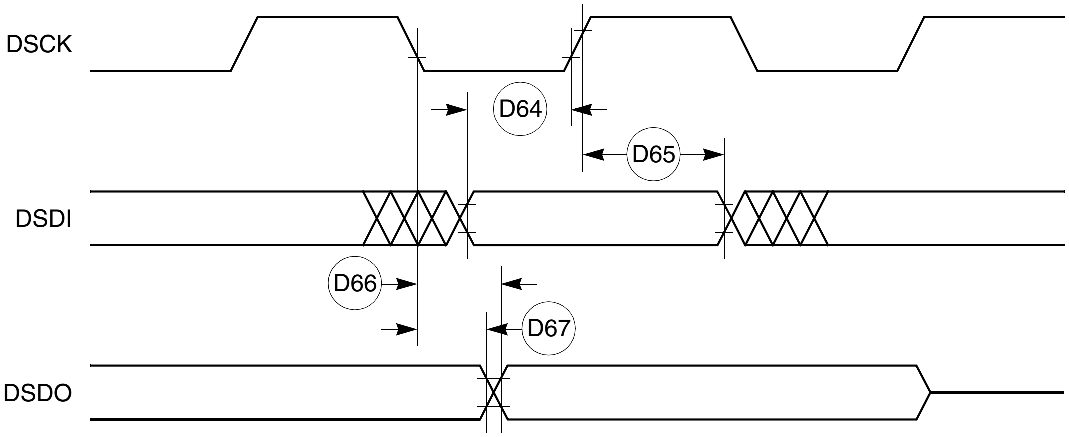

Figure 31. Debug Port Timings

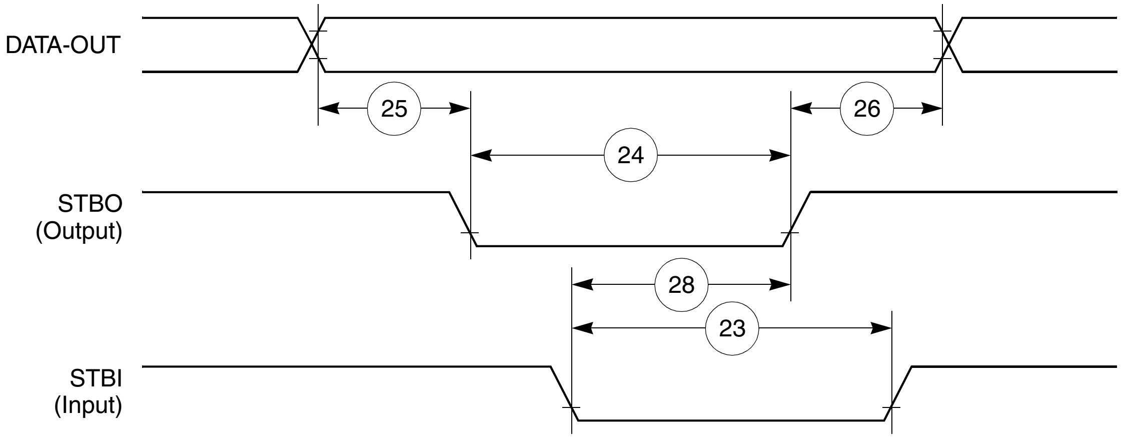

Figure 40. PIP Tx (Interlock Mode) Timing Diagram

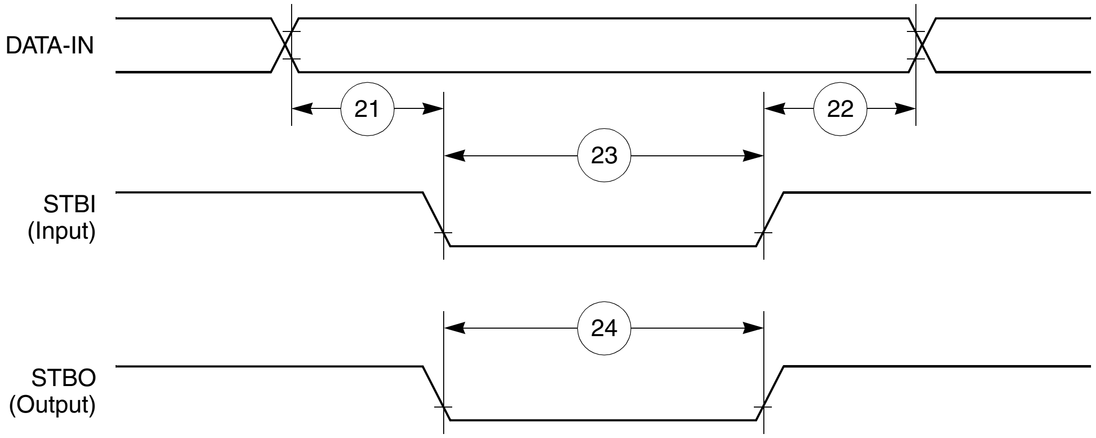

Figure 41. PIP Rx (Pulse Mode) Timing Diagram

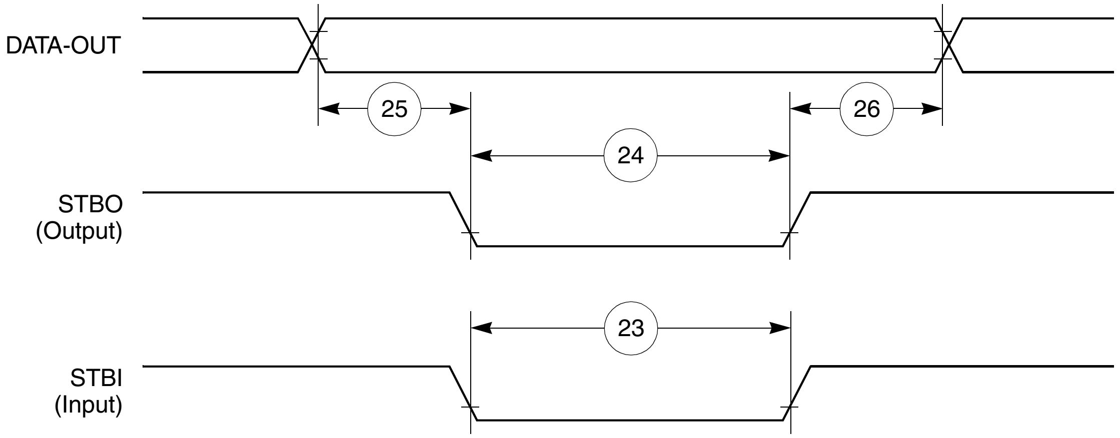

Figure 42. PIP TX (Pulse Mode) Timing Diagram

Table 16. IDMA Controller Timing (continued)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
42	$\overline{\text{SDACK}}$ assertion delay from clock high	—	12	ns
43	$\overline{\text{SDACK}}$ negation delay from clock low	—	12	ns
44	$\overline{\text{SDACK}}$ negation delay from $\overline{\text{TA}}$ low	—	20	ns
45	$\overline{\text{SDACK}}$ negation delay from clock high	—	15	ns
46	$\overline{\text{TA}}$ assertion to rising edge of the clock setup time (applies to external $\overline{\text{TA}}$)	7	—	ns

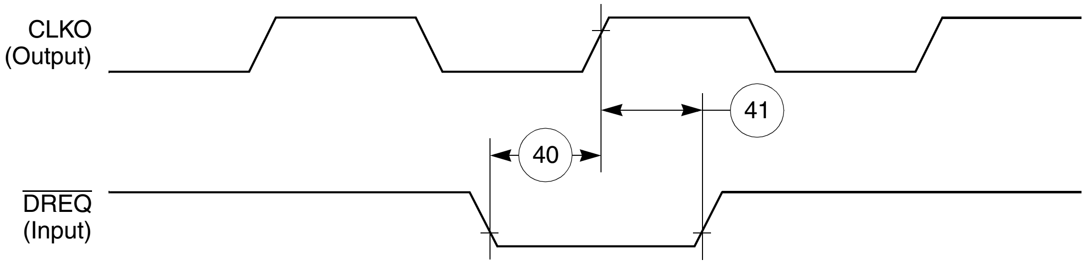

Figure 45. IDMA External Requests Timing Diagram

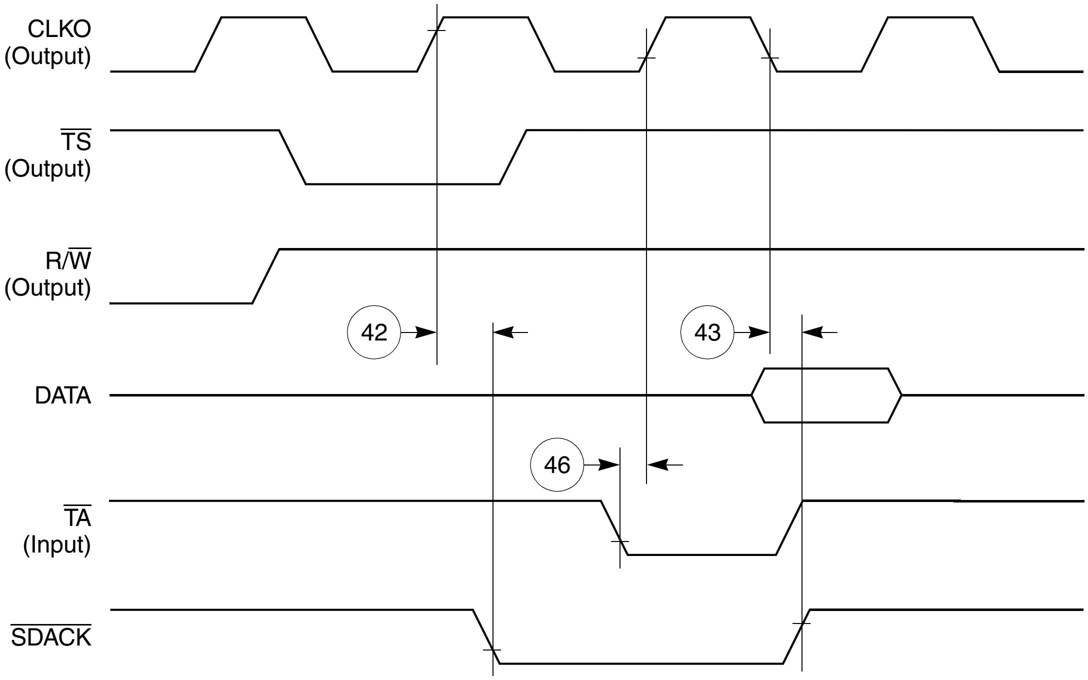

Figure 46. $\overline{\text{SDACK}}$ Timing Diagram—Peripheral Write, Externally-Generated $\overline{\text{TA}}$

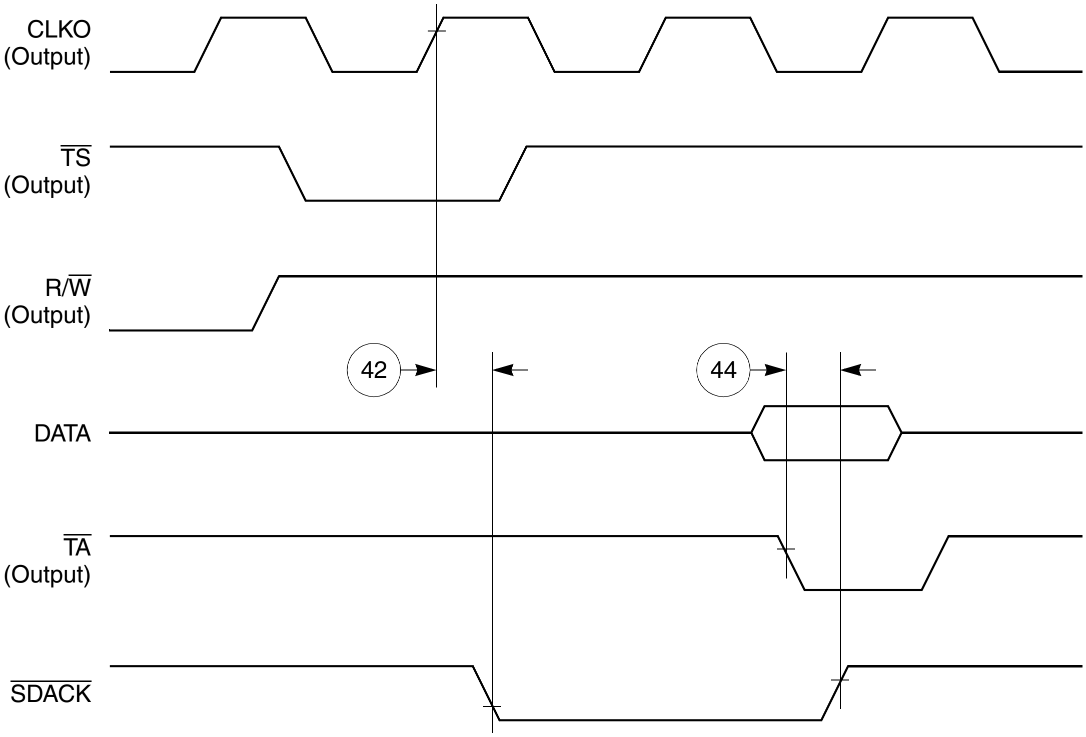

Figure 47. $\overline{\text{SDACK}}$ Timing Diagram—Peripheral Write, Internally-Generated $\overline{\text{TA}}$

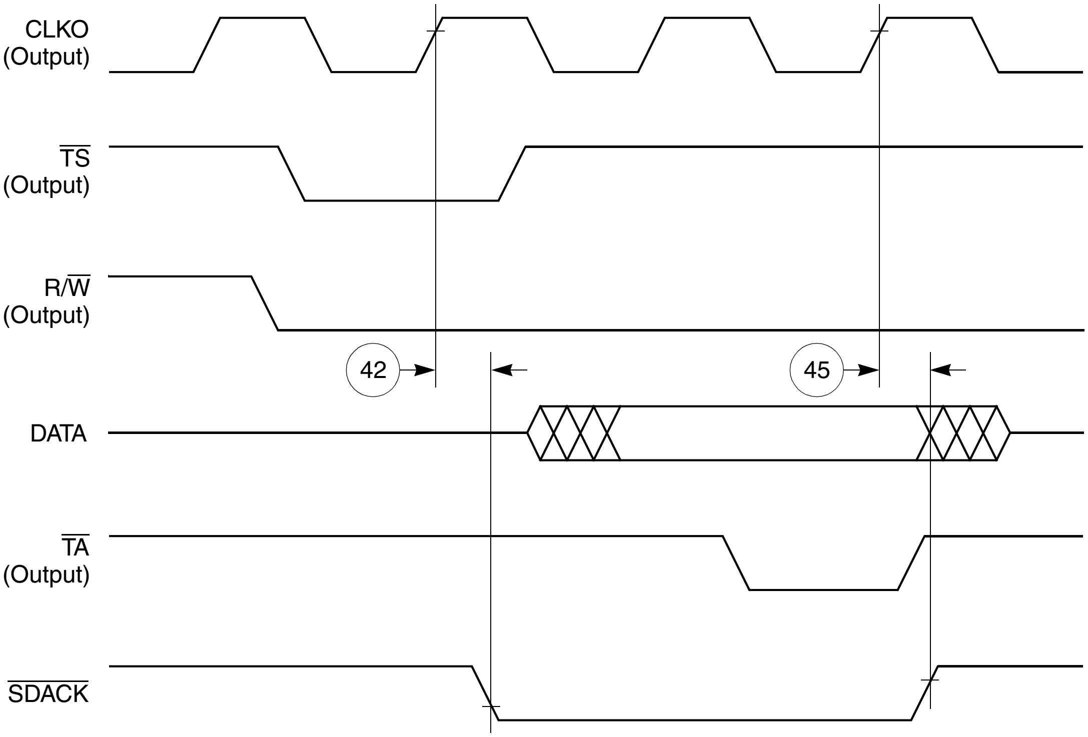

Figure 48. $\overline{\text{SDACK}}$ Timing Diagram—Peripheral Read, Internally-Generated $\overline{\text{TA}}$

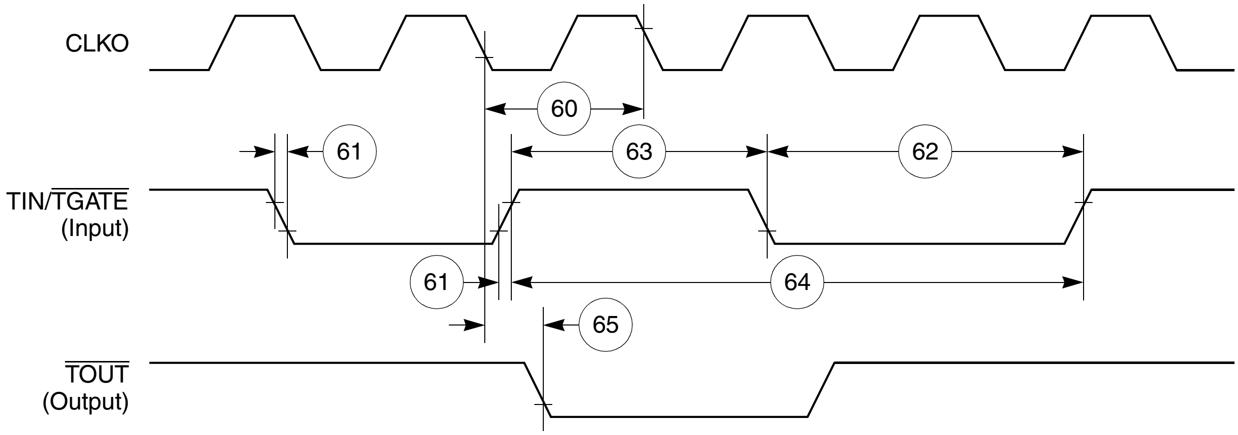

Figure 50. CPM General-Purpose Timers Timing Diagram

11.6 Serial Interface AC Electrical Specifications

Table 19 provides the serial interface timings as shown in Figure 51 through Figure 55.

Table 19. SI Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
70	L1RCLK, L1TCLK frequency (DSC = 0)[1, 2]	—	SYNCCLK/2.5	MHz
71	L1RCLK, L1TCLK width low (DSC = 0)[2]	P + 10	—	ns
71a	L1RCLK, L1TCLK width high (DSC = 0)[3]	P + 10	—	ns
72	L1TXD, L1ST(1–4), $\overline{\text{L1RQ}}$, L1CLKO rise/fall time	—	15.00	ns
73	L1RSYNC, L1TSYNC valid to L1CLK edge (SYNC setup time)	20.00	—	ns
74	L1CLK edge to L1RSYNC, L1TSYNC, invalid (SYNC hold time)	35.00	—	ns
75	L1RSYNC, L1TSYNC rise/fall time	—	15.00	ns
76	L1RXD valid to L1CLK edge (L1RXD setup time)	17.00	—	ns
77	L1CLK edge to L1RXD invalid (L1RXD hold time)	13.00	—	ns
78	L1CLK edge to L1ST(1–4) valid [4]	10.00	45.00	ns
78A	L1SYNC valid to L1ST(1–4) valid	10.00	45.00	ns
79	L1CLK edge to L1ST(1–4) invalid	10.00	45.00	ns
80	L1CLK edge to L1TXD valid	10.00	55.00	ns
80A	L1TSYNC valid to L1TXD valid [4]	10.00	55.00	ns
81	L1CLK edge to L1TXD high impedance	0.00	42.00	ns
82	L1RCLK, L1TCLK frequency (DSC =1)	—	16.00 or SYNCCLK/2	MHz
83	L1RCLK, L1TCLK width low (DSC = 1)	P + 10	—	ns
83a	L1RCLK, L1TCLK width high (DSC = 1)[3]	P + 10	—	ns

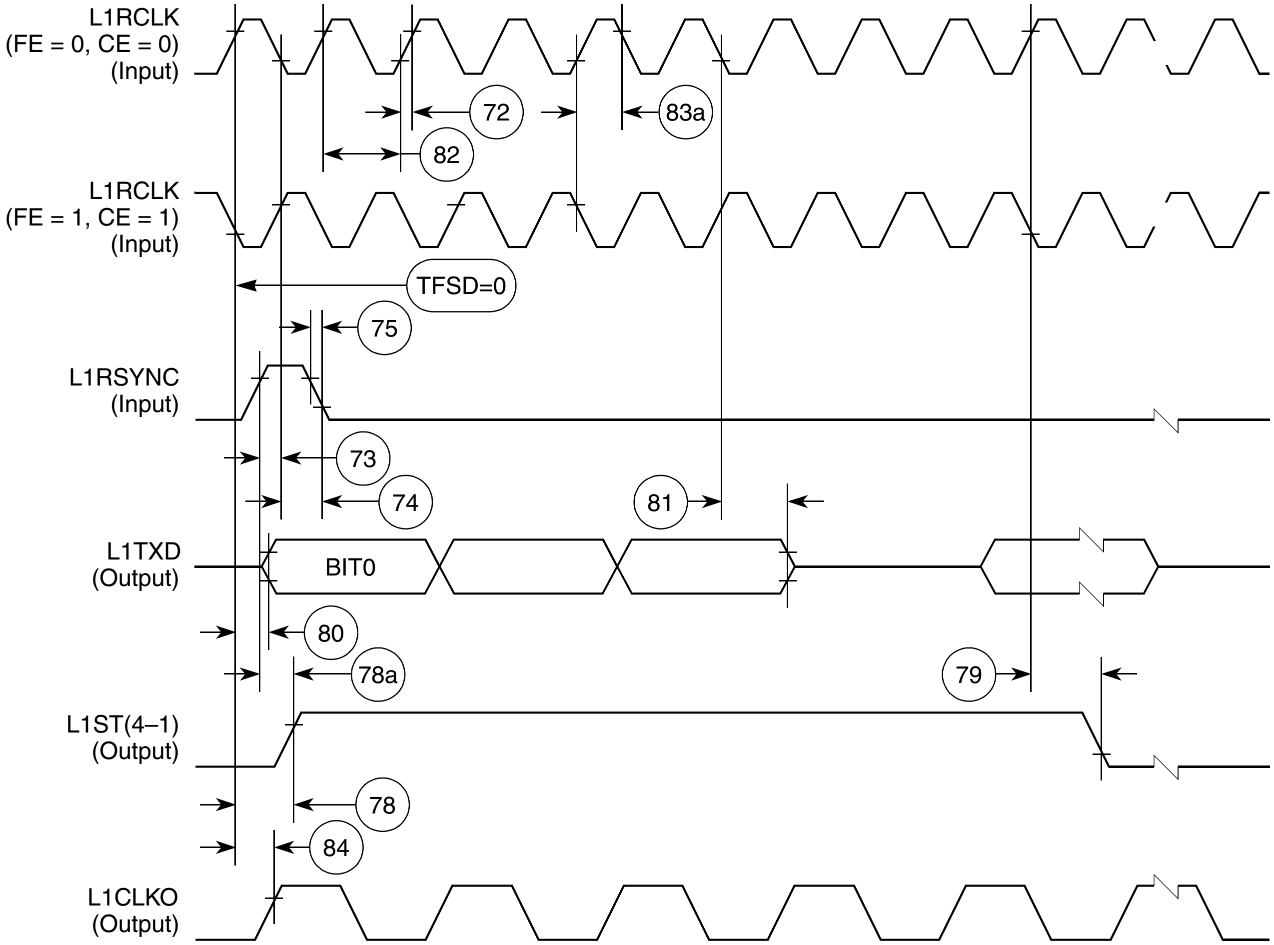

Figure 54. SI Transmit Timing with Double Speed Clocking (DSC = 1)

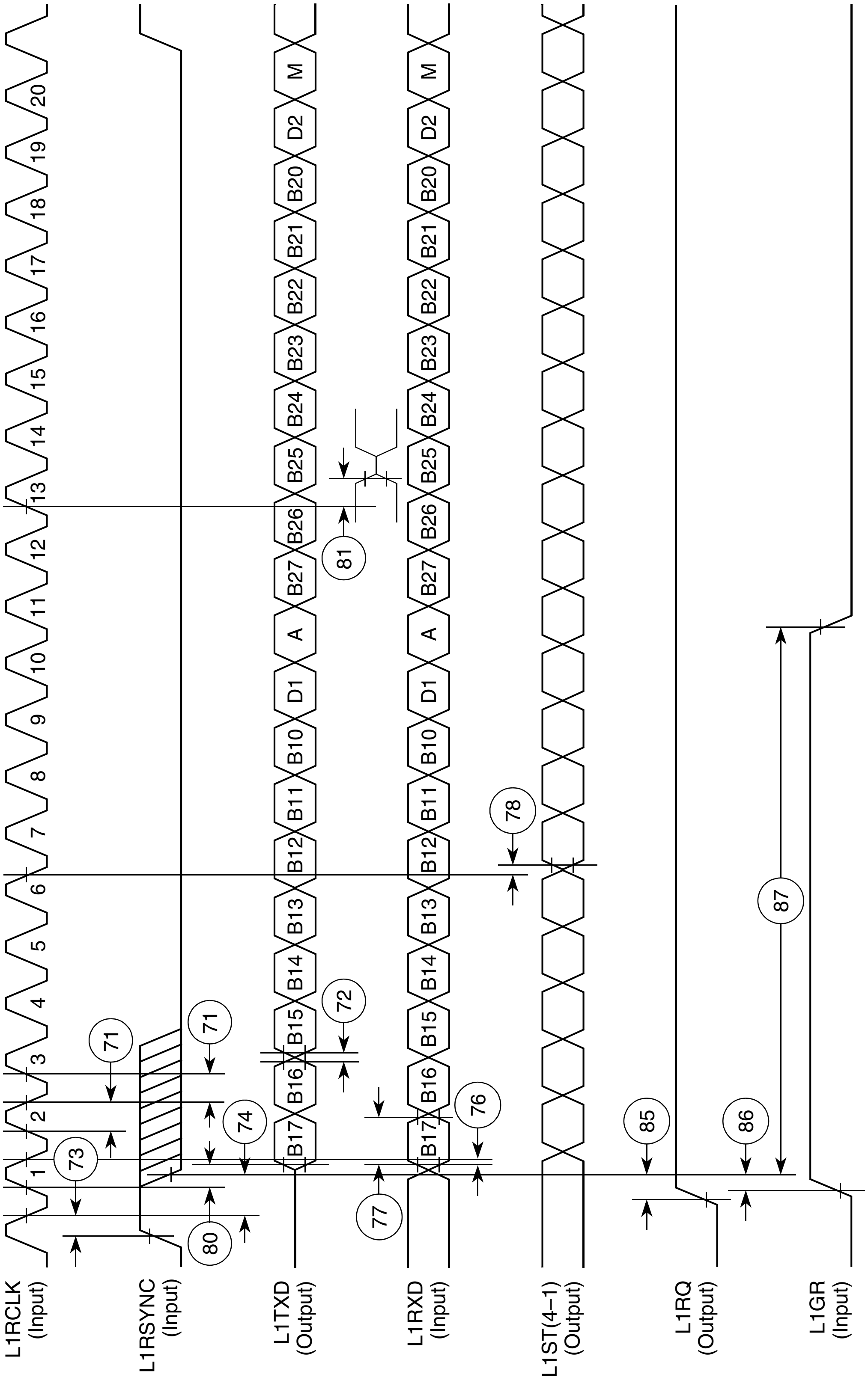

Figure 55. IDL Timing

11.7 SCC in NMSI Mode Electrical Specifications

Table 20 provides the NMSI external clock timing.

Table 20. NMSI External Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK1 and TCLK1 width high[1]	1/SYNCCLK	—	ns
101	RCLK1 and TCLK1 width low	1/SYNCCLK + 5	—	ns
102	RCLK1 and TCLK1 rise/fall time	—	15.00	ns
103	TXD1 active delay (from TCLK1 falling edge)	0.00	50.00	ns
104	$\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge)	0.00	50.00	ns
105	$\overline{\text{CTS1}}$ setup time to TCLK1 rising edge	5.00	—	ns
106	RXD1 setup time to RCLK1 rising edge	5.00	—	ns
107	RXD1 hold time from RCLK1 rising edge[2]	5.00	—	ns
108	$\overline{\text{CD1}}$ setup Time to RCLK1 rising edge	5.00	—	ns

[1] The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 2.25/1.

[2] Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

Table 21 provides the NMSI internal clock timing.

Table 21. NMSI Internal Clock Timing

Num	Characteristic	All Frequencies		Unit
		Min	Max	
100	RCLK1 and TCLK1 frequency[1]	0.00	SYNCCLK/3	MHz
102	RCLK1 and TCLK1 rise/fall time	—	—	ns
103	TXD1 active delay (from TCLK1 falling edge)	0.00	30.00	ns
104	$\overline{\text{RTS1}}$ active/inactive delay (from TCLK1 falling edge)	0.00	30.00	ns
105	$\overline{\text{CTS1}}$ setup time to TCLK1 rising edge	40.00	—	ns
106	RXD1 setup time to RCLK1 rising edge	40.00	—	ns
107	RXD1 hold time from RCLK1 rising edge[2]	0.00	—	ns
108	$\overline{\text{CD1}}$ setup time to RCLK1 rising edge	40.00	—	ns

[1] The ratios SYNCCLK/RCLK1 and SYNCCLK/TCLK1 must be greater than or equal to 3/1.

[2] Also applies to $\overline{\text{CD}}$ and $\overline{\text{CTS}}$ hold time when they are used as external sync signals.

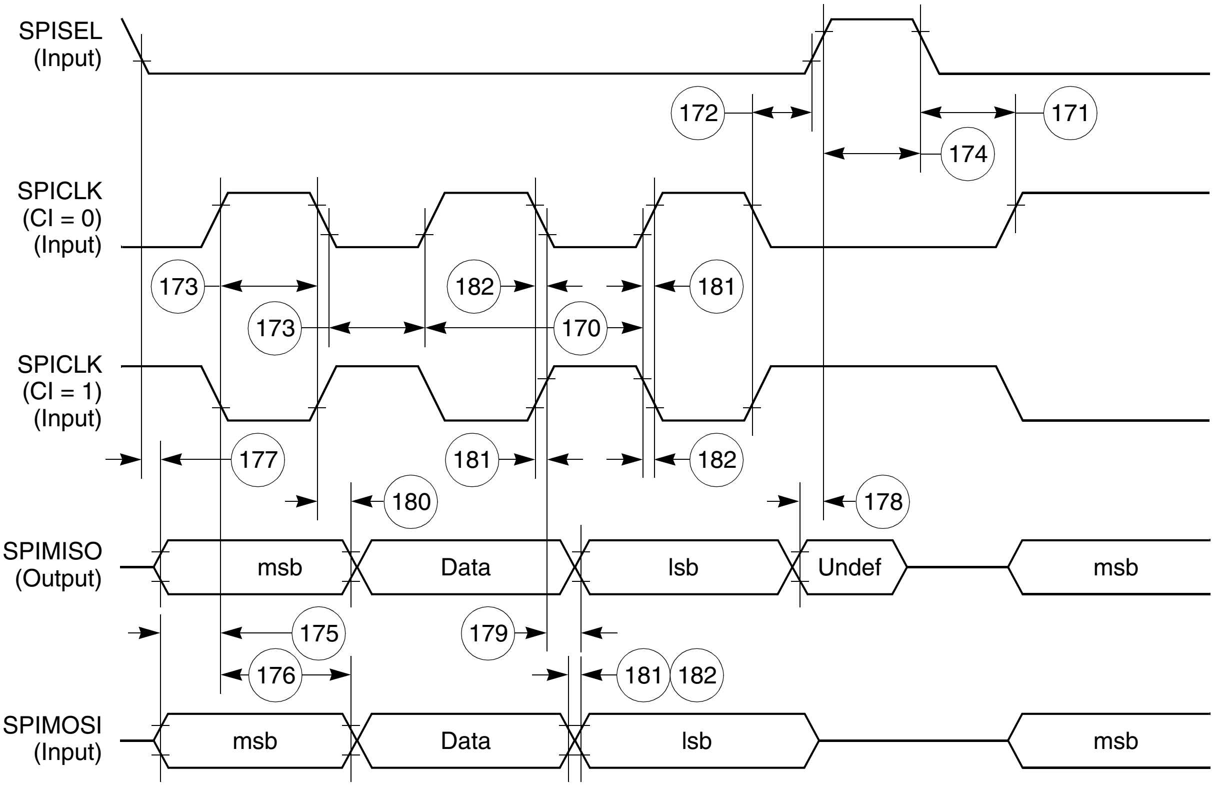

Figure 67. SPI Slave (CP = 0) Timing Diagram

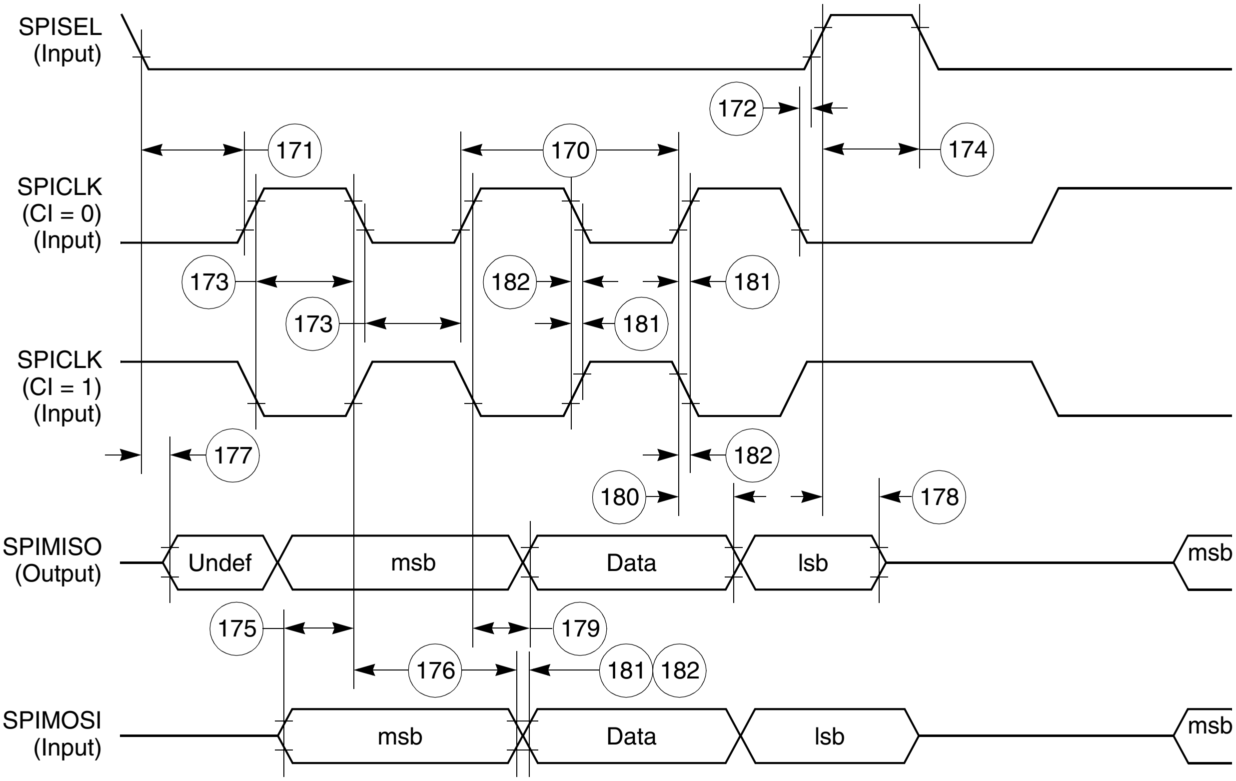

Figure 68. SPI Slave (CP = 1) Timing Diagram

11.12 I^{2}C AC Electrical Specifications

Table 26 provides the I^{2}C (SCL < 100 kHz) timings.

Table 26. I^{2}C Timing (SCL < 100 kHz)

Num	Characteristic	All Frequencies		Unit
		Min	Max	
200	SCL clock frequency (slave)	0	100	kHz
200	SCL clock frequency (master)[1]	1.5	100	kHz
202	Bus free time between transmissions	4.7	—	μs
203	Low period of SCL	4.7	—	μs
204	High period of SCL	4.0	—	μs
205	Start condition setup time	4.7	—	μs
206	Start condition hold time	4.0	—	μs
207	Data hold time	0	—	μs
208	Data setup time	250	—	ns
209	SDL/SCL rise time	—	1	μs
210	SDL/SCL fall time	—	300	ns
211	Stop condition setup time	4.7	—	μs

[1] SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3 × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK/pre_scaler) must be greater than or equal to 4/1.

Table 27 provides the I^{2}C (SCL > 100 kHz) timings.

Table 27. . I^{2}C Timing (SCL > 100 kHz)

Num	Characteristic	Expression	All Frequencies		Unit
			Min	Max	
200	SCL clock frequency (slave)	fSCL	0	BRGCLK/48	Hz
200	SCL clock frequency (master)[1]	fSCL	BRGCLK/16512	BRGCLK/48	Hz
202	Bus free time between transmissions		1/(2.2 * fSCL)	—	s
203	Low period of SCL		1/(2.2 * fSCL)	—	s
204	High period of SCL		1/(2.2 * fSCL)	—	s
205	Start condition setup time		1/(2.2 * fSCL)	—	s
206	Start condition hold time		1/(2.2 * fSCL)	—	s
207	Data hold time		0	—	s
208	Data setup time		1/(40 * fSCL)	—	s
209	SDL/SCL rise time		—	1/(10 * fSCL)	s
210	SDL/SCL fall time		—	1/(33 * fSCL)	s
211	Stop condition setup time		1/2(2.2 * fSCL)	—	s

[1] SCL frequency is given by SCL = BRGCLK_frequency / ((BRG register + 3) × pre_scaler × 2).
The ratio SYNCCLK/(BRGCLK / pre_scaler) must be greater than or equal to 4/1.

13.2 MII Transmit Signal Timing (MII_TXD[3:0], MII_TX_EN, MII_TX_ER, MII_TX_CLK)

The transmitter functions correctly up to a MII_TX_CLK maximum frequency of 25 MHz +1%. There is no minimum frequency requirement. In addition, the processor clock frequency must exceed the MII_TX_CLK frequency – 1%.

Table 30 provides information on the MII transmit signal timing.

Table 30. MII Transmit Signal Timing

Num	Characteristic	Min	Max	Unit
M5	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER invalid	5	—	ns
M6	MII_TX_CLK to MII_TXD[3:0], MII_TX_EN, MII_TX_ER valid	—	25	
M7	MII_TX_CLK pulse width high	35	65%	MII_TX_CLK period
M8	MII_TX_CLK pulse width low	35%	65%	MII_TX_CLK period

Figure 73 shows the MII transmit signal timing diagram.

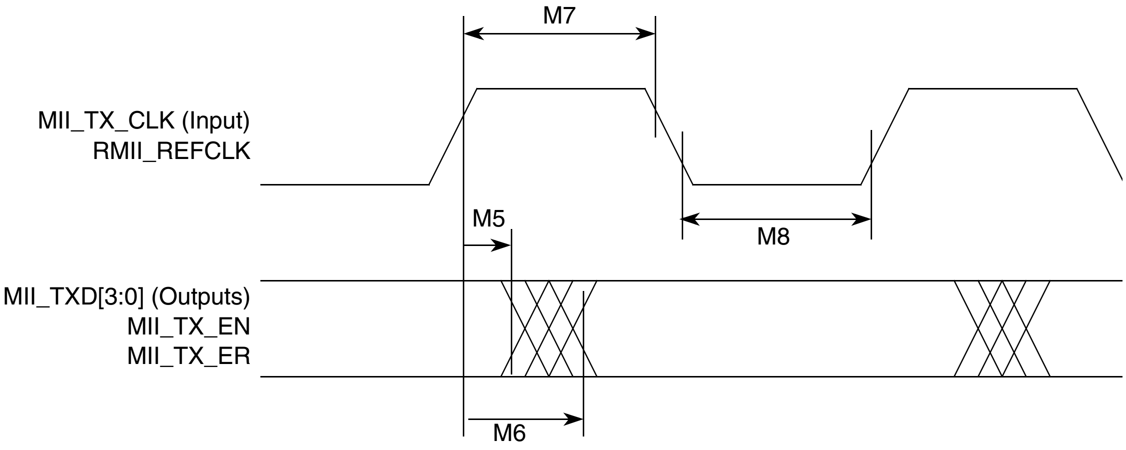

Figure 73. MII Transmit Signal Timing Diagram

13.3 MII Async Inputs Signal Timing (MII_CRS, MII_COL)

Table 31 provides information on the MII async inputs signal timing.

Table 31. MII Async Inputs Signal Timing

Num	Characteristic	Min	Max	Unit
M9	MII_CRS, MII_COL minimum pulse width	1.5	—	MII_TX_CLK period

Figure 74 shows the MII asynchronous inputs signal timing diagram.

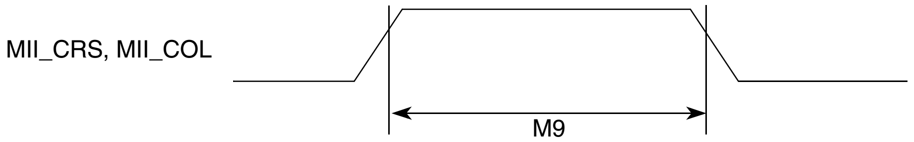

Figure 74. MII Async Inputs Timing Diagram

13.4 MII Serial Management Channel Timing (MII_MDIO, MII_MDC)

Table 32 provides information on the MII serial management channel signal timing. The FEC functions correctly with a maximum MDC frequency in excess of 2.5 MHz. The exact upper bound is under investigation.

Table 32. MII Serial Management Channel Timing

Num	Characteristic	Min	Max	Unit
M10	MII_MDC falling edge to MII_MDIO output invalid (minimum propagation delay)	0	—	ns
M11	MII_MDC falling edge to MII_MDIO output valid (max prop delay)	—	25	ns
M12	MII_MDIO (input) to MII_MDC rising edge setup	10	—	ns
M13	MII_MDIO (input) to MII_MDC rising edge hold	0	—	ns
M14	MII_MDC pulse width high	40%	60%	MII_MDC period
M15	MII_MDC pulse width low	40%	60%	MII_MDC period

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Document Number: MPC860EC
Rev. 10
09/2015